

March 1994 Revised November 1999

74ABT16373

16-Bit Transparent D-Type Latch with 3-STATE Outputs

General Description

The ABT16373 contains sixteen non-inverting latches with 3-STATE outputs and is intended for bus oriented applications. The device is byte controlled. The flip-flops appear transparent to the data when the Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the setup time is latched. Data appears on the bus when the Output Enable ($\overline{\text{OE}}$) is LOW. When $\overline{\text{OE}}$ is HIGH, the outputs are in high Z state.

Features

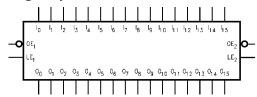
- Separate control logic for each byte
- 16-bit version of the ABT373
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Guaranteed latch-up protection

Ordering Code:

Order Number	Package Number	Package Description
74ABT16373CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT16373CMTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbol



Pin Descriptions

Pin Names	Description
OE n	Output Enable Input (Active LOW)
LE _n	Latch Enable Input
D ₀ -D ₁₅	Data Inputs
O ₀ -O ₁₅	Outputs

Connection Diagram



Functional Description

The ABT16373 contains sixteen D-type latches with 3-STATE standard outputs. The device is byte controlled with each byte functioning identically, but independent of the other. Control pins can be shorted together to obtain full 16-bit operation. The following description applies to each byte. When the Latch Enable (LEn) input is HIGH, data on the D_{n} enters the latches. In this condition the latches are transparent, i.e., a latch output will change states each time its D input changes. When $\operatorname{LE}_{\operatorname{n}}$ is LOW, the latches store information that was present on the D inputs a setup time preceding the HIGH-to-LOW transition of $\rm LE_n$. The 3-STATE standard outputs are controlled by the Output Enable (\overline{OE}_n) input. When \overline{OE}_n is LOW, the standard outputs are in the 2-state mode. When \overline{OE}_n is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

Truth Tables

	Inputs		Outputs
LE ₁	OE ₁	D ₀ -D ₇	0 ₀ –0 ₇
Х	Н	Х	Z
Н	L	L	L
Н	L	Н	Н
L	L	Χ	(Previous)

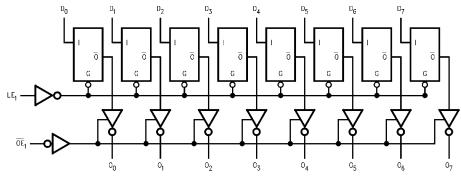
	Inputs		Outputs
LE ₂	ŌE ₂	D ₈ -D ₁₅	O ₈ -O ₁₅
Χ	Н	Х	Z
Н	L	L	L
Н	L	Н	Н
L	L	Χ	(Previous)

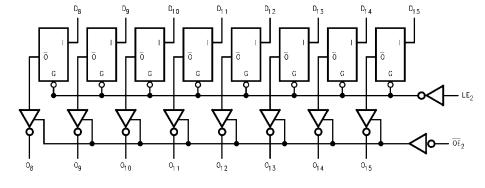
H = HIGH Voltage Level

- L = LOW Voltage Level
- X = Immaterial Z = High Impedance

Previous = previous output prior to HIGH-to-LOW transition of LE

Logic Diagrams





Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

-65°C to +150°C Storage Temperature -55°C to +125°C Ambient Temperature under Bias

 $-55^{\circ}C$ to $+150^{\circ}C$ Junction Temperature under Bias V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to +5.5Vin the HIGH State $-0.5 \mbox{V to V}_{\mbox{CC}}$

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA) -350 mA DC Latchup Source Current: OE Pin

(Across Comm Operating Range) Other Pins

Over Voltage Latchup (I/O)

-40°C to +85°C Free Air Ambient Temperature Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate (ΔV/Δt)

Data Input 50 mV/ns Enable Input 20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device
-500 mA may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

10V Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Param	eter	Min	Тур	Max	Units	V _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Vol	tage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage		2.5				Min	$I_{OH} = -3 \text{ mA}$
			2.0				IVIIII	$I_{OH} = -32 \text{ mA}$
V _{OL}	Output LOW Voltage				0.55	V	Min	I _{OL} = 64 mA
I _{IH}	Input HIGH Current				1	μА	Max	V _{IN} = 2.7V (Note 3)
					1	μΛ	IVIAX	$V_{IN} = V_{CC}$
I _{BVI}	Input HIGH Current Br	eakdown Test			7	μΑ	Max	V _{IN} = 7.0V
I _{IL}	Input LOW Current				-1	μА	Max	V _{IN} = 0.5V (Note 3)
					-1	μΛ	IVIAX	$V_{IN} = 0.0V$
V _{ID}	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \mu A$
								All Other Pins Grounded
I _{OZH}	Output Leakage Curre	nt			10	μΑ	0 – 5.5V	V _{OUT} = 2.7V; OE = 2.0V
I _{OZL}	Output Leakage Curre	nt			-10	μΑ	0 – 5.5V	V _{OUT} = 0.5V; OE = 2.0V
Ios	Output Short-Circuit C	urrent	-100		-275	mA	Max	V _{OUT} = 0.0V
I _{CEX}	Output HIGH Leakage	Current			50	μΑ	Max	$V_{OUT} = V_{CC}$
I _{ZZ}	Bus Drainage Test				100	μΑ	0.0	V _{OUT} = 5.5V; All Others GND
I _{CCH}	Power Supply Current				2.0	mA	Max	All Outputs HIGH
I _{CCL}	Power Supply Current				62	mA	Max	All Outputs LOW
I _{CCZ}	Power Supply Current				2.0	mA	Max	OE = V _{CC}
								All Others at V _{CC} or GND
Ісст	Additional I _{CC} /Input	Outputs Enabled			2.5	mA		$V_1 = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input V _I = V _{CC} - 2.1V
		Outputs 3-STATE			2.5	mA		Data Input V _I = V _{CC} - 2.1V
								All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC}	No Load				mA/		Outputs Open, LE = V _{CC}
	(Note 3)				0.15	MHz	Max	OE = GND, (Note 4)
								One Bit Toggling, 50% Duty Cycle

Note 3: Guaranteed, but not tested.

Note 4: For 8 bits toggling, $I_{CCD} < 0.8 \text{ mA/MHz}.$

AC Electrical Characteristics

(SOIC and SSOP Packages)

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	•
t _{PLH}	Propagation Delay	1.4		5.6	1.4	5.6	ns
t _{PHL}	D _n to O _n	1.4		5.6	1.4	5.6	115
t _{PLH}	Propagation Delay	1.7		6.0	1.7	6.0	ns
t _{PHL}	LE to O _n	1.7		5.5	1.7	5.5	115
t _{PZH}	Output Enable Time	1.1		6.1	1.1	6.1	ns
t _{PZL}		1.5		5.6	1.5	5.6	115
t _{PHZ}	Output Disable Time	2.4		7.1	2.4	7.1	ns
t _{PLZ}		1.6		6.5	1.6	6.5	115

AC Operating Requirements

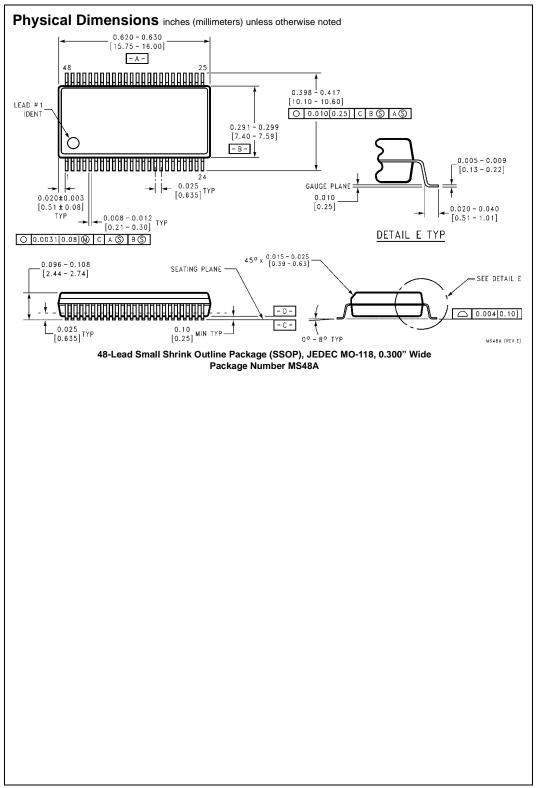
(SOIC and SSOP Packages)

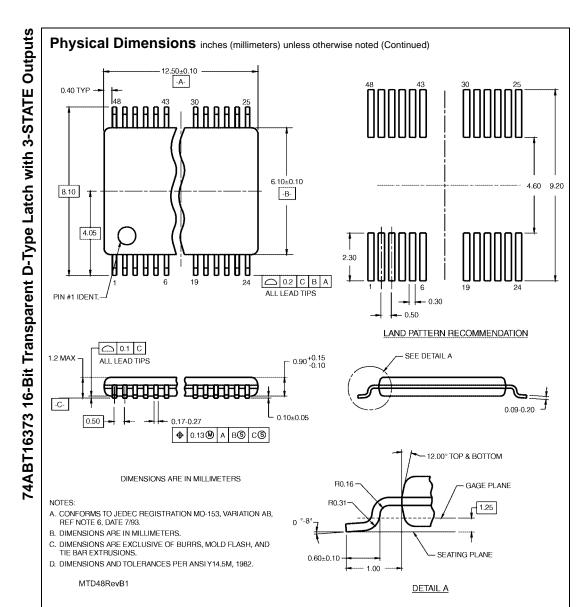
Symbol	Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		
		Min	Тур	Max	Min	Max		
f _{TOGGLE}	Maximum Toggle Frequency		100				MHz	
t _S (H)	Setup Time, HIGH	1.5			1.5			
$t_S(L)$	or LOW D _n to LE	1.5			1.5		ns	
t _H (H)	Hold Time, HIGH	1.0			1.0			
t _H (L)	or LOW D _n to LE	1.0			1.0		ns	
t _W (H)	Pulse Width, LE HIGH	3.0			3.0		ns	

Capacitance

Symbol	Parameter	Тур	Units	Conditions (T _A = 25°C)
C _{IN}	Input Capacitance	5	pF	V _{CC} = 0V
C _{OUT} (Note 5)	Output Capacitance	11	pF	$V_{CC} = 5.0V$

Note 5: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.





48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide Package Number MTD48

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